Electronic Supplementary Material (ESI) for RSC Advances.

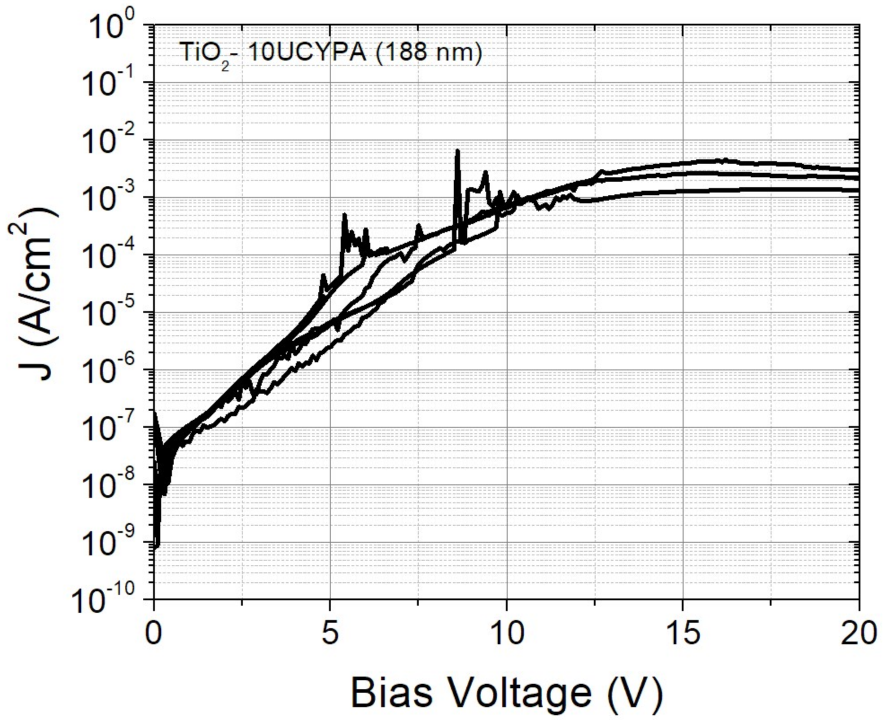

Figure 1. Leakage current through a 188 nm TiO_2 - 10UCYPA thin film measured in air. Measurements were done on 3-4 fresh (unstressed) devices.

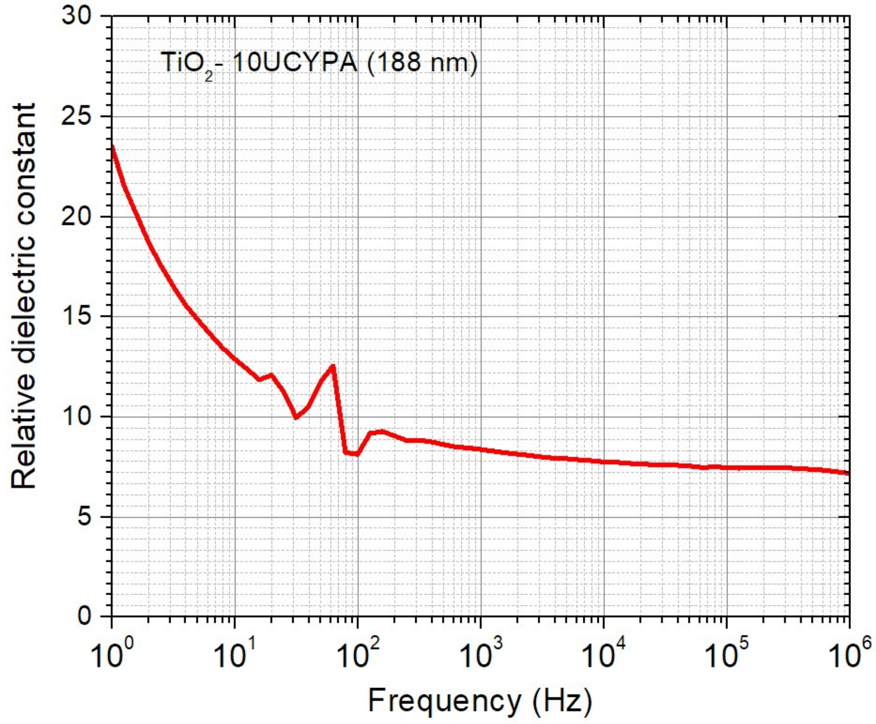

Figure 2. Relative dielectric constant of a 188 nm TiO_2 - 10UCYPA thin film measured in air. The noise at around 50Hz is originating from the power grid.

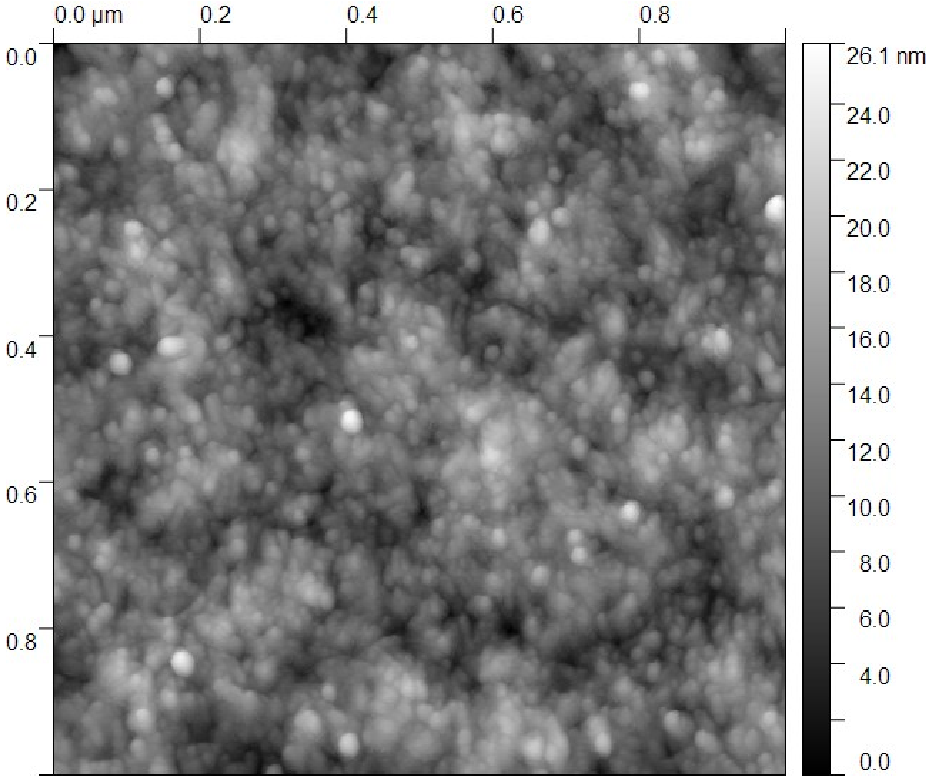

Figure 3. AFM scan of a TiO_2 – OA thin film